

Search Notes

Application/Control No.

09/612,136

Examiner

QI HAN

Applicant(s)/Patent under
Reexamination

NAGANO ET AL.

Art Unit

2626

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR